### 查询SN74LS593供应商

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SN54LS592, SN54LS593, SN74LS592, SN74LS593 8-BIT BINARY COUNTERS WITH INPUT REGISTERS

SDLS004 D2633, JANUARY 1981-REVISED MARCH 1988

- Parallel Register Inputs ('LS592)
- Parallel 3-State I/O: Register Inputs/ Counter Outputs ('LS593)
- Counter has Direct Overriding Load and Clear
- Accurate Counter Frequency: DC to 20 MHz

#### description

The 'LS592 comes in a 16-pin package and consists of a parallel input, 8-bit storage register feeding an 8-bit binary counter. Both the register and the counter have individual positive-edge-triggered clocks. In addition, the counter has direct load and clear functions. A low-going RCO pulse will be obtained when the counter reaches the hex word FF. Expansion is easily accomplished for two stages by connecting RCO of the first stage to CCKEN of the second stage. Cascading for larger count chains can be accomplished by connecting RCO of each stage to CCK of the following stage.

The 'LS593 comes in a 20-pin package and has all the features of the 'LS592 plus 3-state I/O, which provides parallel counter outputs. The tables below show the operation of the enable (CCKEN,  $\overline{\text{CCKEN}}$ ) inputs. A register clock enable ( $\overline{\text{RCKEN}}$ ) is also provided.

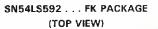
#### OUTPUT ENABLE CONTROL ('593 ONLY)

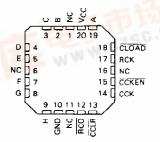
	G	G	$A/Q_A$ thru $H/Q_H$
ĺ	L	L	input mode
	L	H	input mode
	н	L	output mode
	н	н	input mode

#### COUNTER CLOCK ENABLE CONTROL

CCKEN	CCKEN	EFFECT ON CCK
Ł	L	Enable
L	н	Disable
н	L	Enable
н	н	Enable





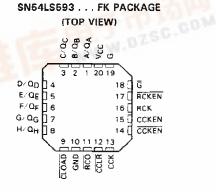


NC - No internal connection

## SN54LS593 ... J OR W PACKAGE SN74LS593 ... DW OR N PACKAGE (TOP VIEW)

AVQA	1	U20	□ vcc
B/QB	2	19	G
c/ac	3	18	οŪ
D/ 0 <sub>D</sub> [	4	17	RCKEN
E/QE	5	16	🗋 яск
F / QF 🗌	6	15	CCKEN
G/ 0 <sub>G</sub> [	7	14	CCKEN
нион 🗍	8	13	_ сск
LOAD	9	12	CCLR
GND	10	11	RCO

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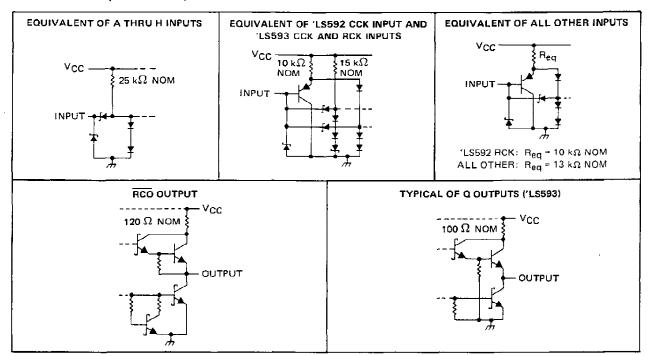


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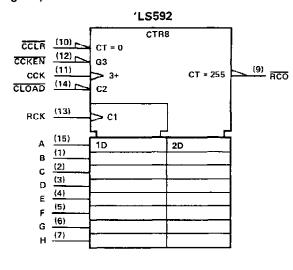
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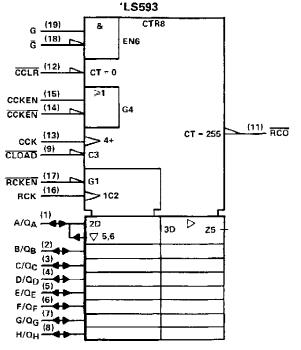


### schematics of inputs and outputs



logic symbols<sup>†</sup>

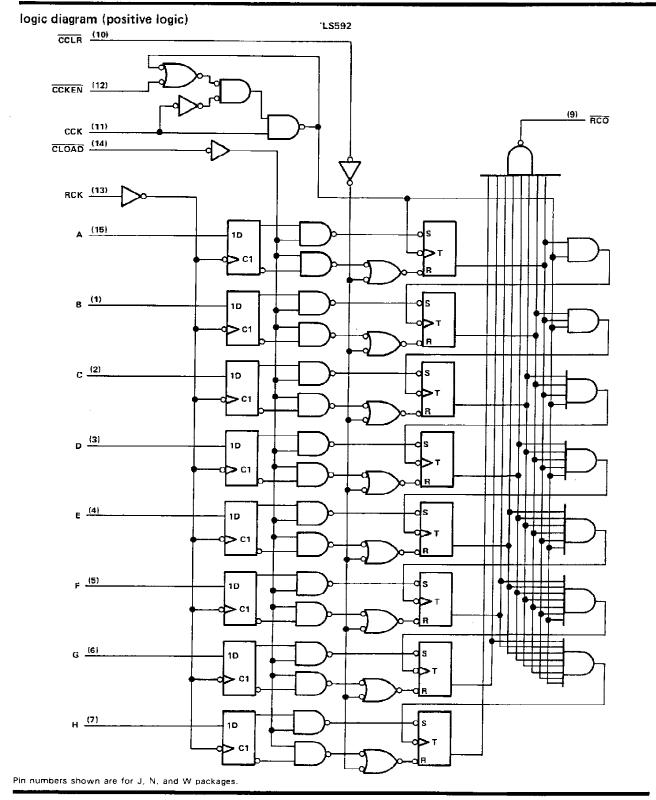




 $^\dagger$  These symbols are in accordance with ANSI/IEEE Std. 91-1984 and IEC Publication 617-12. Pin numbers shown are for DW, J, N, and W packages.



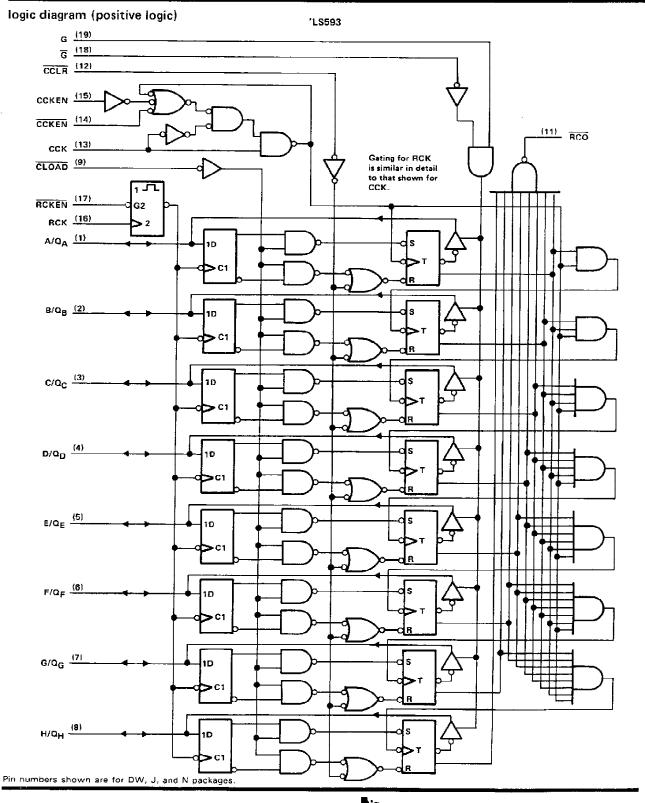
## SN54LS592, SN74LS592 8-BIT BINARY COUNTERS WITH INPUT REGISTERS



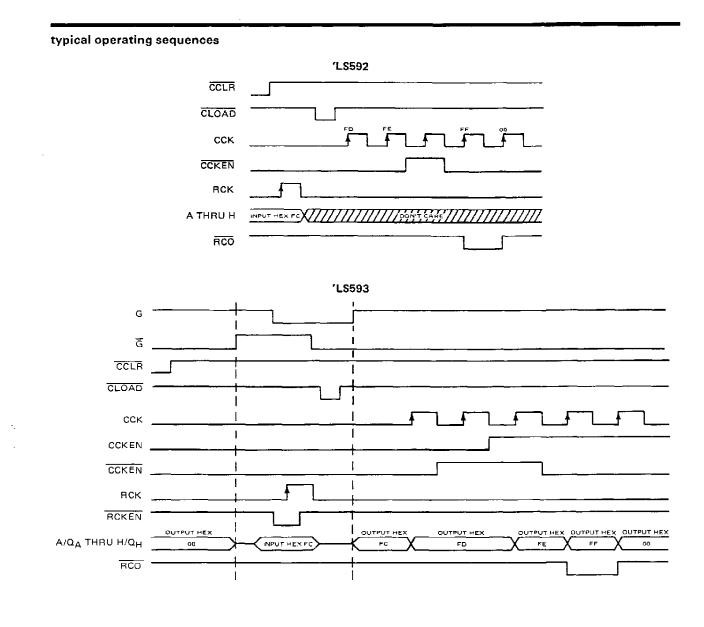
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# SN54LS593, SN74LS593 8-BIT BINARY COUNTERS WITH INPUT REGISTERS



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### absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, VCC (see Note 1)	7 V
Input voltage (excluding I/O ports)	7V
Off-state output voltage (including I/O ports)	5.5 V
Operating free-air temperature range: SN54LS592, SN54LS593	- 55°C to 125°C
SN74LS592, SN74LS593	$\dots$ 0°C to 70°C
Storage temperature range	- 65°C to 150°C

 $^\circ$  NOTE 1: Voltage values are with respect to the network ground terminal.

### recommended operating conditions

				SN54LS		SN74LS'			UNIT	
-			MIN NOM MAX MIN NOM MA				MAX			
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.25	V	
V <sub>IH</sub>	High-level input voltage		2			2			v	
VIL	Low-level input voltage			· · ·	0.7			0.8	V	
المار		RCO			- 1			- 1	mA	
юн	High-level output current	Q'LS593 only			- 1		· · ·	- 2.6		
<sup>1</sup> 0L	Low-level output current	RCO			8			16	<u> </u>	
'UL		Q 'LS593 only			12			24	mA	
fcck	Counter clock frequency		0		20	0		20	MHz	
t <sub>w</sub> (CCK)	Duration of counter clock p	uise	25			25			ns	
tw (CCLR)	Duration of counter clear pu	20			2D			ns		
tw (RCK)	Duration of register clock pulse					20			ns	
tw (CLOAD	Duration of counter load pu	lse	40			40			ns	
t <sub>su</sub>	Register enable setup time	RCKEN low to RCK 1, 'LS593	20			20			ns	
	Counter enable setup time	CCKEN low, 'LS592	30			30			1	
t <sub>su</sub>	before CCK t	CCKEN low or CCKEN high, 'LS593	30			30		0.8 - 1 - 2.6 16 24	ns	
		CCLR inactive before CCK t	20			20				
tsu	Setup time	CLOAD inactive before CCK 1	20			20				
-su		RCK t before CLOAD t (see Note 2)	30			30			ns	
		Data A thru H before RCK †	20			20				
th	Hold time	Data A thru H after RCK †	0			Q				
·11	····	All others	0			0			ns	
TA	Operating free-air temperatu	re	- 55		125	0		70	°C	

NOTE 2: This time insures the data saved by RCK  $\uparrow$  will also be loaded into the counter.

	D4 D 4 145750	TEST CONDITION	unt	SI	N54LS'	_	5	SN74LS		UNIT
	PARAMETER	TEST CONDITION	MIN	TYP‡	MAX	( MIN	TYP‡	MAX	UNIT	
Viĸ		V <sub>CC</sub> = MIN, I <sub>I</sub> = -18 mA				- 1.5			- 1.5	V
	'LS593 Q	$v_{CC} = MIN,  v_{IH} = 2 V,$	l <sub>OH</sub> = −1 mA	2.4	3.2					
∨он	23333 2	$V_{CC} = MAX$	I <sub>OH</sub> = -2.6 mA				2.4	3.1		v
	RCO		$I_{OH} = -1 \text{ mA}$	2.4	3.2		2.4	3.2		
ļ.	1LS593 Q		1 <sub>OL</sub> = 12 mA		0.25	0.4		0.25	0.4	
Voi		$V_{CC} = MIN, V_{IH} = 2 V,$	I <sub>OL</sub> = 24 mA					0.35	0.5	v
	RCO	V <sub>IL</sub> = MAX	I <u>OL</u> = 8 mA		0.25	0.4		0.25	0.4	-
			I <sub>OL</sub> = 16 mA					0.35	0.5	
Iоzн	'LS593 Q	$V_{CC} = MAX, V_{IH} = 2 V,$ $V_O = 2.7 V$	-			20			20	μA
lozl	'LS593 Q	$V_{CC} = MAX, V_{IH} = 2 V,$ $V_{O} = 0.4 V$	V <sub>IL</sub> = MAX,			-0.4			- 0.4	mA
	'LS593 Q		VI = 5.5 V			0.1			0.1	mА
11	Others	V <sub>CC</sub> = MAX	V <sub>1</sub> = 7 V			0.1			0.1	mA
<sup>‡</sup> iH		$V_{CC} = MAX, V_1 = 2.7 V$				20			20	μA
	ССК					-0.8			-0.8	
	RCK LS592					-0.2			- 0.2	
VIK VOH VOL IOZH II IIL III IOS <sup>§</sup>	1LS593	$V_{CC} = MAX$ , $V_{I} = 0.4 V$				- <b>0</b> .8			- 0.8	mA
	A thru H					-0.4			-0.4	
	Others					-0.2			-0.2	
loc§	'LS593 Q	$V_{CC} = MAX, V_{O} = 0 V$		- 30		- 130	- 30	_	- 130	mA
.05	RCO			- 20		- 100	- 20		- 100	
	′LS592 <sup>/</sup> ССН				40	60		40	60	
	ICCL	$V_{CC} = MAX,$	puts grounded,		40	60		40	60	
lcc	ССН	All possible inputs grounded,			47	70		47	70	
	'LS593 ICCL	All outputs open			53	80	-	53	80	
	l lccz				57	85	L	57	85	

### electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

TFor conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

<sup>‡</sup>All typical values are at V<sub>CC</sub> = 5 V, T<sub>A</sub> = 25 °C.

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<sup>5</sup>Not more than one output should be shorted at a time and the duration of the short-circuit should not exceed one second.



	FROM	то			T	LS592		'LS593			
PARAMETER	(INPUT)	(OUTPUT)	TEST COND	MIN	TYP	MAX	MIN	ТҮР	MAX	UNIT	
†max	сск	RCO	R_=1kΩ,	Ci_ = 30 pF	20	35		20	35		MHz
<sup>t</sup> PLH	CCK1	Q							14	21	ns
tPHL	CCK1	Q							26	39	ns
трГН	CLOAD +	Q							34	51	ns
tPHL.	CLOAD +	Q		Cլ = 45 pF					28	42	ns
tPHL	CCLR +	٩	R <sub>L</sub> = 667 Ω,						25	38	ns
<sup>t</sup> PZH	Gt	Q							31	47	ns
TPZL	Gt	a							27	40	រាទ
<sup>t</sup> PZH	<u>G</u> ↓	۵							29	45	ns
tPZL.	G i	٩							31	47	ns
<sup>†</sup> PHZ	G↓	a		С <b>_</b> = 5 рF					33	50	ns
<sup>t</sup> PLZ	Gł	٥							35	52	ns
<sup>t</sup> PHZ	Gt	٩	$H = 567 \Omega_{c}$						26	39	ns
<sup>t</sup> PLZ	٥t	Q							28	42	ns
tPLH	CCK t	RCO				15	23		14	21	ns
<sup>t</sup> PHL	CCK 1	RCO				20	30		20	30	ns
<b>t</b> PLH	CLOAD +	RCO	R <sub>L</sub> = 1 kΩ,	C <sub>L</sub> = 30 pF		31	47		31	47	ns
tPHL	CLOAD +	RCO	1			27	41		27	41	ns
t₽LH	CCLR +	RCO				30	45		30	45	ns
<sup>t</sup> PLH	RCK 1	ਸਟਹ	$R_L = 1 k\Omega;$	CL = 30 pF		35	53		42	63	ns
<sup>t</sup> PHL	RCK t	RCO	CLOAD = L			30	45		33	50	ns

### switching characteristics, V<sub>CC</sub> = 5 V, T<sub>A</sub> = $25^{\circ}$ C, (see note 3)

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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